Docket No.: ARL 00-25

Art Unit:

Examiner:

Application of:

Tidrow, et al

Serial No.: 10/087,766

Filed: 03/05/02

For: Apparatus for Precision Measurement of

Microwave Material Properties

As Functions of Temperature and Frequency

Commissioner of Patents and Trademarks Office

Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

In accordance with 37 CFR §§1.56, 1.97 and 1.98 applicants hereby call to the attention of the Examiner the references cited on the PTO-1449, attached hereto.

These citations do not constitute an admission that the references are relevant or material to the claims. They are cited only as constituting the closest art of which the Applicants are aware.

Respectfully submitted,

William V. Adams

Attorney for Applicants

Reg. No.: 32,552

U.S. Army Research Laboratory ATTN: AMSRL-CS-CC-IP

2800 Powder Mill Road

Adelphi, Maryland 20783-1197

29 MARCH 2002



			- VOZE	ENARE	I			_		
PTO Form 1449					APPLICATION NUMBER		10/08	10/087,766		
DATE OF A STATE OF A S					FILING DATE	03/05/	03/05/02			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					FIRST NAMED INVENTOR		Tidro	Tidrow, et al		
					GROUP ART UNIT					
					EXAMINER NAME					
SHEET	1	OF	1	ATTOR	NEY DOCKET NUMB	, <u>, , , , , , , , , , , , , , , , , , </u>	ARL 00-25			
Examine initials	l l	U.S. Patent Number		Name of Patentee or A Cited Document		Patent Date	Class	Subclass	Filing Date	
					و المعالية					
				FOF	REIGN PATENT D	OCUMEN	ITS			
			a Maria							
OTHER	INFORM	ATION	l (includ	ing autho	or, title, date, pertine	ent pages.	etc.)			
1A	"The A	ccurat	e Measu	rement o	f Permittivity by Mo d. A. 325, 493-509	eans of an		onator," A.l	L. Cullen	
	EC									
							- indicate the second	7	7 77	
								<u> </u>	. 10	
						DA	ATE CONSIDERED:			
EXAMI	NER:					DA	TE CONS	incigen.		